

General Description

The TF070P03M combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$.

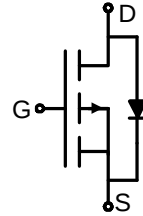
Features

Advance high cell density Trench technology
Low $R_{DS(ON)}$ to minimize conductive loss
Low Gate Charge for fast switching
Low Thermal resistance

Application

MB/VGA Vcore
SMPS 2nd Synchronous Rectifier
POL application
BLDC Motor driver

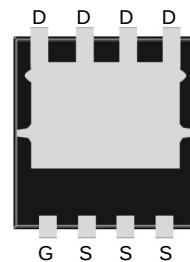
Product Summary



$$V_{DS} = -30V \quad I_D = -60A$$

$$R_{DS(ON)}(-10V \text{ typ}) = 7.5m\Omega$$

$$R_{DS(ON)}(-4.5V \text{ typ}) = 11m\Omega$$



PDFNWB3.3x3.3-8L

Ordering Information:

Part NO.	TF070P03M
Marking1	070P03M
Marking2	TF:tuofeng; Y:year code; X:Week; AA:device code;
Basic ordering unit (pcs)	5000

Absolute Maximum Ratings ($T_C = 25^\circ C$)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	$I_{D@T_C=25^\circ C}$	-60	A
	$I_{D@T_C=75^\circ C}$	-42	A
	$I_{D@T_C=100^\circ C}$	-36	A
Pulsed Drain Current ^①	I_{DM}	-180	A
Total Power Dissipation ^②	$P_D@T_C=25^\circ C$	50	W
Total Power Dissipation	$P_D@T_A=25^\circ C$	2.0	W
Operating Junction Temperature	T_J	-55 to 150	$^\circ C$
Storage Temperature	T_{STG}	-55 to 150	$^\circ C$

● Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case ^②	R_{thJC}	-	-	3.5	° C/W
Thermal resistance, junction - ambient	R_{thJA}	-	-	50	° C/W
Soldering temperature, wavesoldering for 8s	T_{sold}	-	-	265	° C

● Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = -250\mu A$	-30			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = -250\mu A$	-1.0	-1.5	-2.0	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS} = -28V, V_{GS} = 0V$			-1.0	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$			± 100	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS} = -10V, I_D = -20A$		7.5	9.0	m Ω
		$V_{GS} = -4.5V, I_D = -15A$		11	14	m Ω
Forward Transconductance	g_{FS}	$V_{DS} = -10V, I_D = -10A$		12		S
Source-drain voltage	V_{SD}	$I_S = -20A$		0.85	1.00	V

● Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C_{iss}	$f = 1MHz$ $V_{DD} = -30V$ $V_{GS} = 0V$	-	2497	-	pF
Output capacitance	C_{oss}		-	240	-	
Reverse transfer capacitance	C_{rss}		-	230	-	

● Gate Charge characteristics ($T_a = 25^\circ C$)

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	Q_g	$V_{DD} = -15V$ $I_D = -20A$ $V_{GS} = -10V$	-	32.0	-	nC
Gate - Source charge	Q_{gs}		-	6.60	-	
Gate - Drain charge	Q_{gd}		-	8.00	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = -10V$ $V_{DD} = -15V$ $R_L = 3.0\Omega$ $I_D = -30A$	-	14.0	-	nS
Turn-On Rise Time	t_r		-	20.0	-	
Turn-Off Delay Time	$t_{d(off)}$		-	56.0	-	
Turn-Off Fall Time	t_f		-	48.0	-	

Note:

① Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;

Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;

P- Channel Typical Characteristics

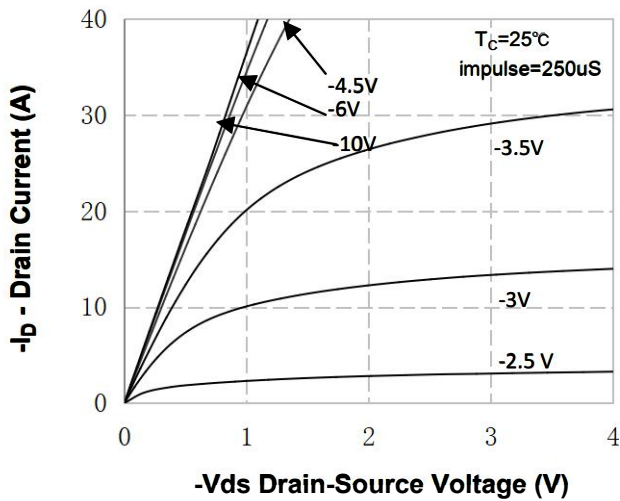


Figure 1. On-Region Characteristics

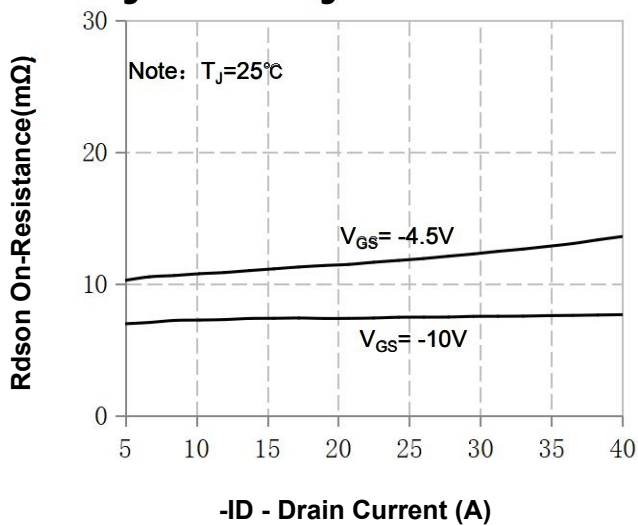


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

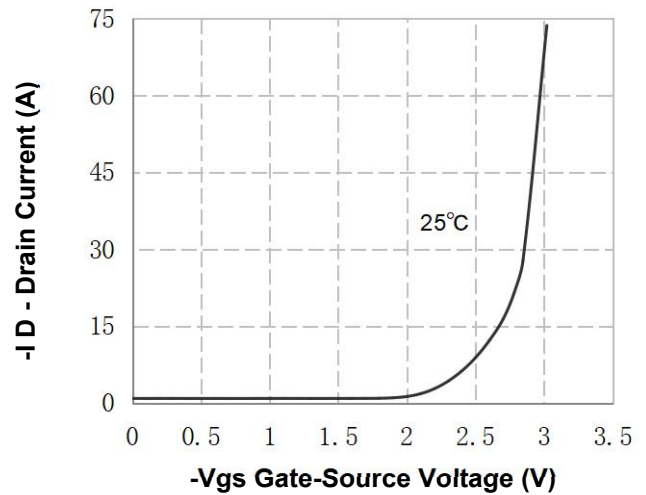


Figure 2. Transfer Characteristics

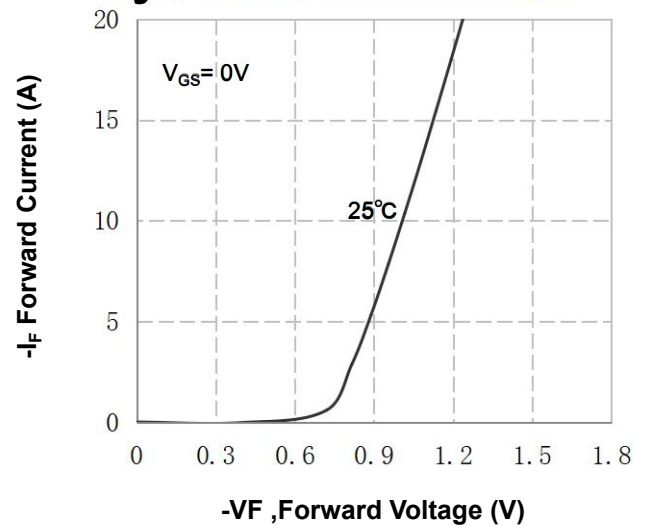


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

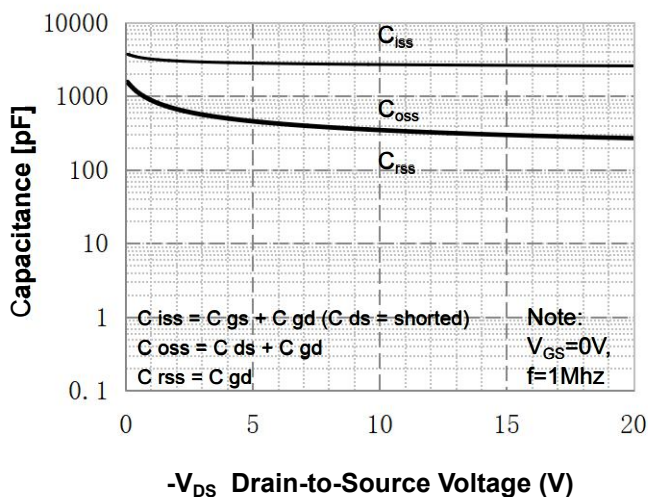


Figure 5. Capacitance Characteristics

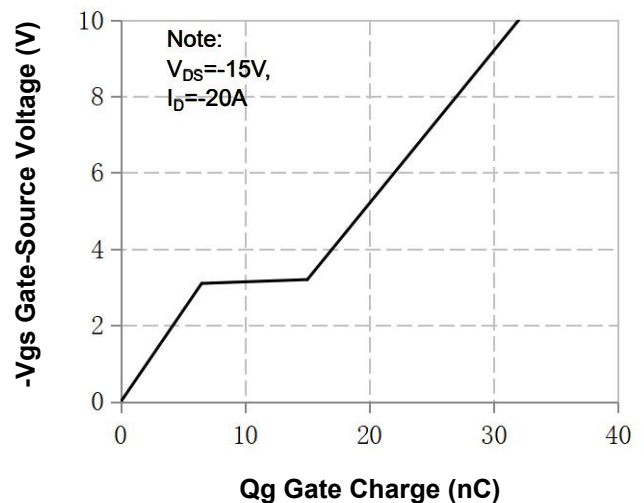


Figure 6. Gate Charge Characteristics

P- Channel Typical Characteristics (Continued)

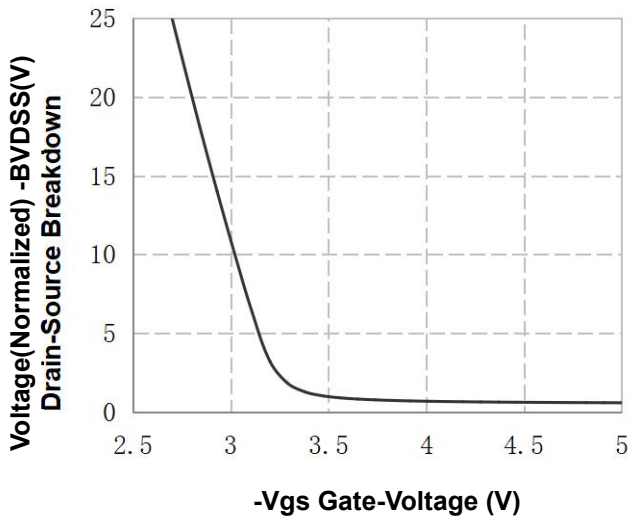


Figure 7. Breakdown Voltage Variation vs Gate-Voltage

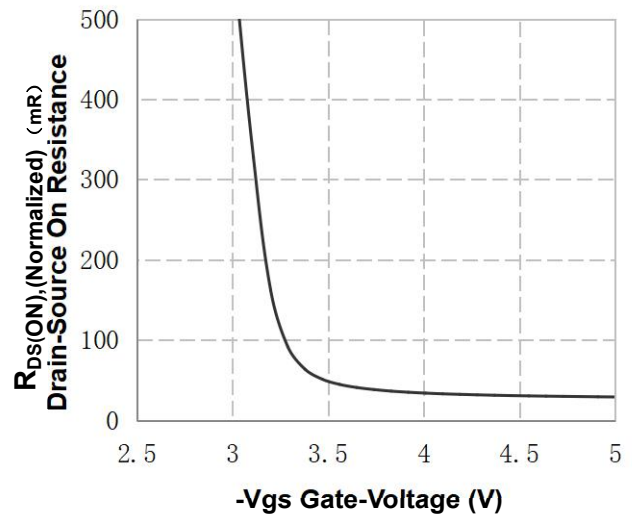


Figure 8. On-Resistance Variation vs Gate Voltage

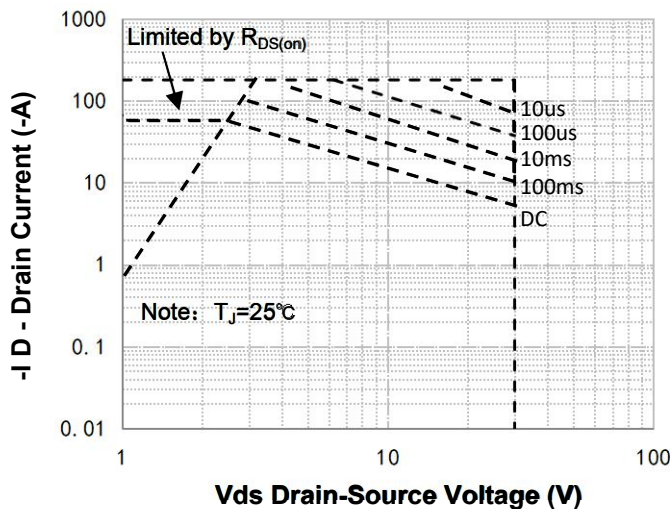


Figure 9. Maximum Safe Operating Area

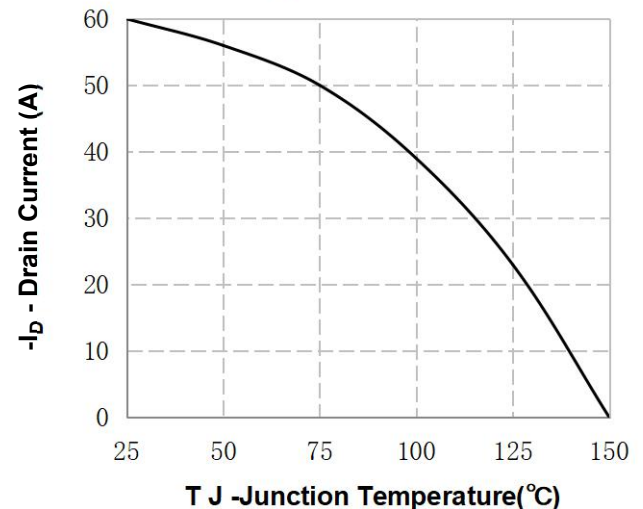


Figure 10. Maximum Continuous Drain Current vs Case Temperature

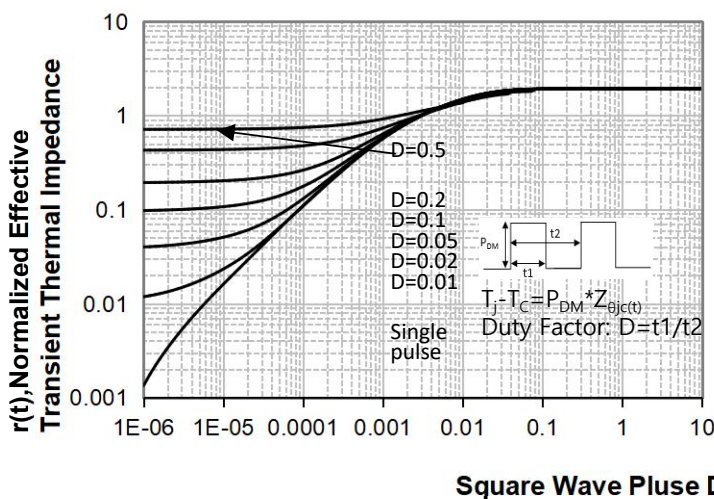
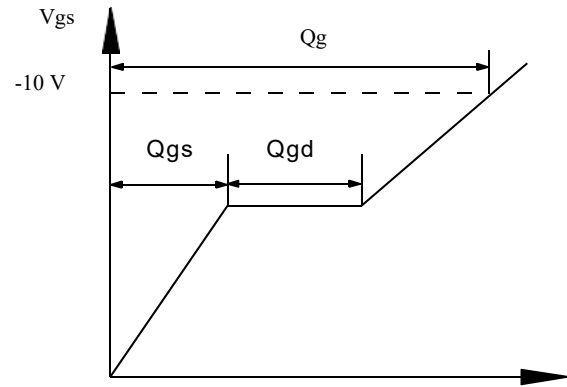
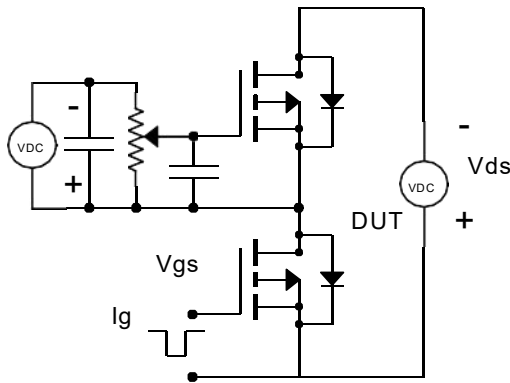
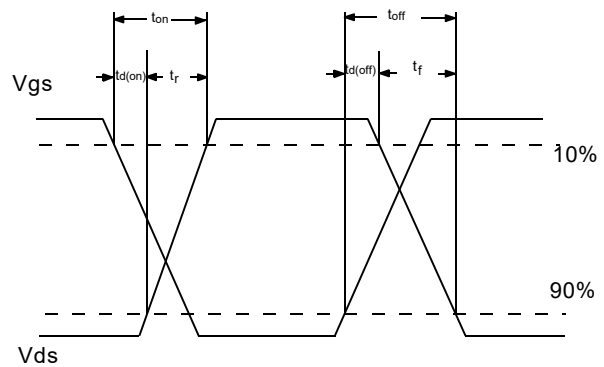
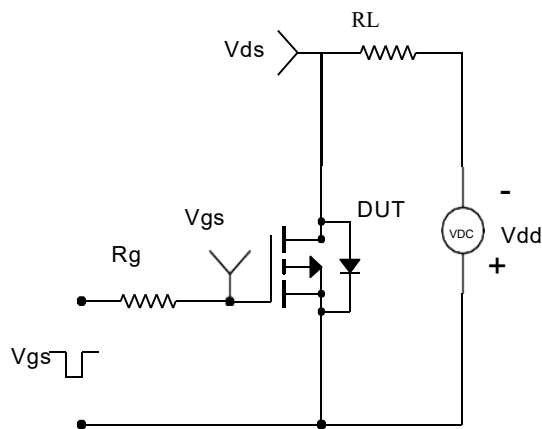


Figure 11. Transient Thermal Response Curve

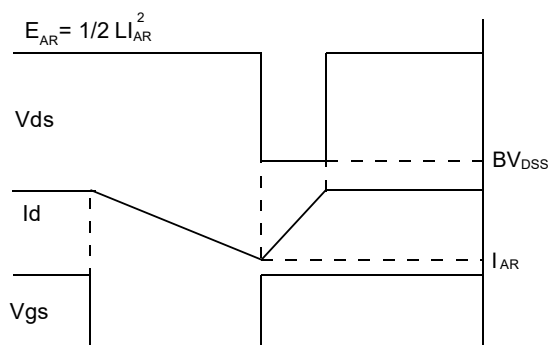
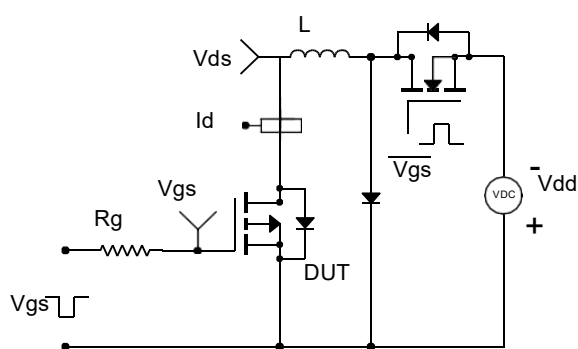
Gate Charge Test Circuit & Waveform



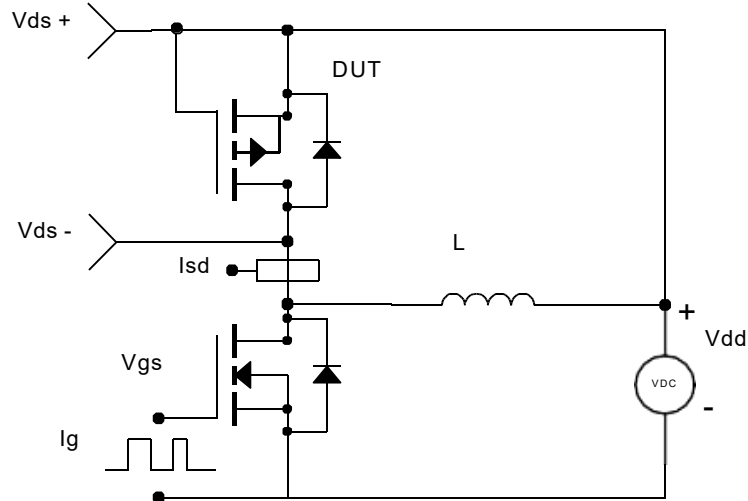
Resistive Switching Test Circuit & Waveforms



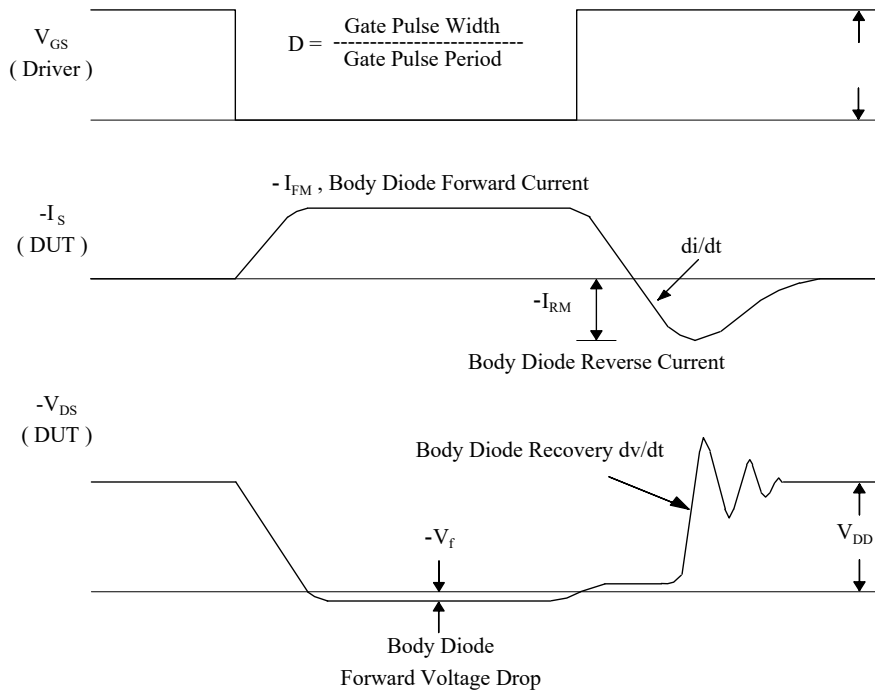
Unclamped Inductive Switching Test Circuit & Waveforms



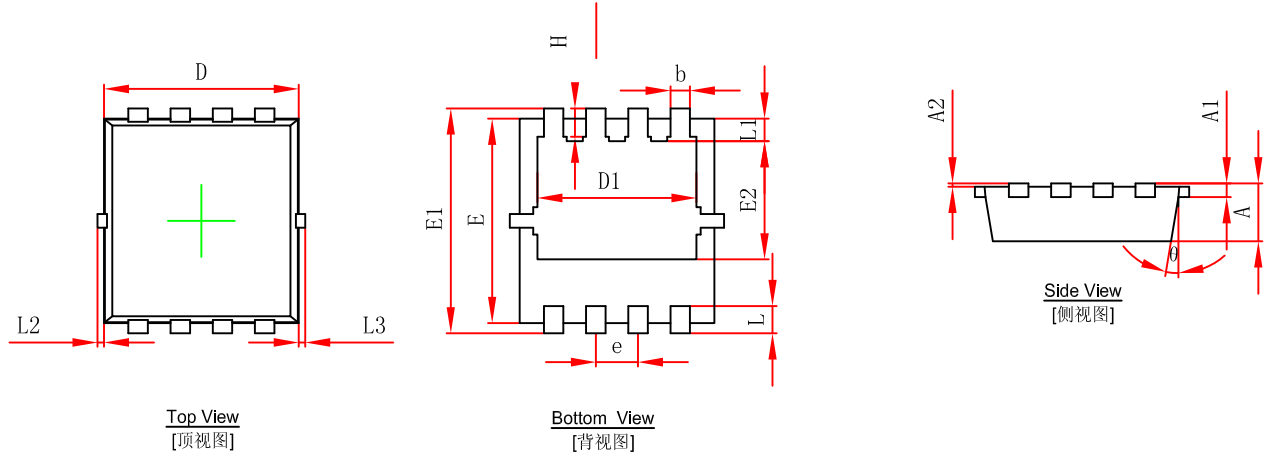
Peak Diode Recovery dv/dt Test Circuit & Waveforms



- dv/dt controlled by R_G
- I_{SD} controlled by pulse period

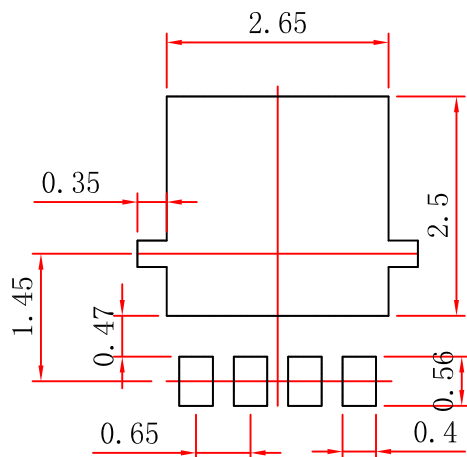


PDFNWB3.3x3.3-8L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
θ	9°	13°	9°	13°

PDFNWB3.3x3.3-8L Suggested Pad Layout



Note:

1. Controlling dimension: in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$.
3. The pad layout is for reference purposes only.